

STS-310 PECVD Film Properties

	Deposition Rate (nm/min)	Refractive index (@632nm)	Etch rate in 6:1 BOE (nm/min)	Etch rate 20:1 HF (nm/min)	Stress (MPa)
High frequency oxide	33	1.48	175		200 compressive
Low frequency oxide	43	1.48	95	65	350 compressive
High frequency nitride	10	2	30		400 tensile
Low frequency nitride	17	2	6		900 compressive
Mixed frequency nitride	11	2	25		60 tensile
a-Silicon (Argon based)	38	3.9	N/A		200 compressive
a-Silicon (Nitrogen based)	13	3.9	N/A		330 compressive